

FOCUSED ION BEAM PROCESS FOR REMOVAL OF COPPER METAL

ABSTRACT OF THE DISCLOSURE

5 A process for milling copper metal from a substrate having an exposed copper surface includes absorbing a halogen gas onto the exposed copper surface to generate reaction products of copper and the halogen gas; removing unreacted halogen gas from the surface; and directing a focused ion beam onto the surface to selectively remove a portion of the surface comprising the reaction products.

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